

<b>Notice of References Cited</b>	Application/Control No. 10/644,827		Applicant(s)/Patent Under Reexamination FUKUDA ET AL.	
	Examiner Ryan Lepisto		Art Unit 2883	Page 1 of 1

#### U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-2002/0076655	06-2002	Borrelli et al.	430/321
*	B	US-2003/0035640	02-2003	Dugan et al.	385/124
*	C	US-6,154,593	11-2000	Miura et al.	385/123
*	D	US-6,573,026	06-2003	Aitken et al.	430/290
	E	US-			
	F	US-			
	G	US-			
	H	US-			
	I	US-			
	J	US-			
	K	US-			
	L	US-			
	M	US-			

#### FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
	P					
	Q					
	R					
	S					
	T					

#### NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	Corning Incorporated, "HPFS Fused Silica KrF Grade", CORNING INCORPORATED, Product Specifications, September 30, 2003, <a href="http://www.corning.com/semiconductoroptics/products_services/pdf/h0607_hpfskrf_productsheet.pdf">http://www.corning.com/semiconductoroptics/products_services/pdf/h0607_hpfskrf_productsheet.pdf</a> . is the specification of the silica ma
	V	
	W	
	X	

\*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)  
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